IEC 60793-1-45

Edition 3.0 2024-04

INTERNATIONAL STANDARD

NORME INTERNATIONALE

Optical fibres –
Part 1-45: Measurement methods and test procedures – Mode field diameter

Fibres optiques –
Partie 1-45 : Méthodes de mesure et procédures d'essai – Diamètre du champ de mode

IEC 60793-1-45:2024-04(en-fr)

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INTERNATIONAL ELECTROTECHNICAL COMMISSION

OPTICAL FIBRES –

Part 1-45: Measurement methods and test procedures – Mode field diameter

FOREWORD

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IEC 60793-1-45 has been prepared by subcommittee 86A: Fibres and cables, of IEC technical committee 86: Fibre optics. It is an International Standard.

This third edition cancels and replaces the second edition published in 2017. This edition constitutes a technical revision.

This edition includes the following significant technical changes with respect to the previous edition:

a) Modification of the minimum distance between the fibre end and the detector for the direct far field scan (Annex A).
b) Generalization of the requirement for the minimum dynamic range for all fibre types (Annex A).

The text of this International Standard is based on the following documents:

Draft	Report on voting
86A/2300/CDV	86A/2366/RVC

Full information on the voting for its approval can be found in the report on voting indicated in the above table.

The language used for the development of this International Standard is English.

This document was drafted in accordance with ISO/IEC Directives, Part 2, and developed in accordance with ISO/IEC Directives, Part 1 and ISO/IEC Directives, IEC Supplement, available at www.iec.ch/members_experts/refdocs. The main document types developed by IEC are described in greater detail at www.iec.ch/publications.

A list of all parts in the IEC 60793 series, published under the general title *Optical fibres*, can be found on the IEC website.

The committee has decided that the contents of this document will remain unchanged until the stability date indicated on the IEC website under webstore.iec.ch in the data related to the specific document. At this date, the document will be

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OPTICAL FIBRES –

Part 1-45: Measurement methods and test procedures – Mode field diameter

1 Scope

This part of IEC 60793 establishes uniform requirements for measuring the mode field diameter (MFD) of single-mode optical fibre, thereby assisting in the inspection of fibres and cables for commercial purposes.

2 Normative references

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 60793-1-40, *Optical fibres – Part 1-40: Attenuation measurement methods*

3 Terms, definitions and abbreviated terms

3.1 Terms and definitions

No terms and definitions are listed in this document.

ISO and IEC maintain terminology databases for use in standardization at the following addresses:

- IEC Electropedia: available at https://www.electropedia.org/
- ISO Online browsing platform: available at https://www.iso.org/obp

3.2 Abbreviated terms

The abbreviated terms are given in Table 1.

Table 1 – Abbreviated terms

Abbreviated term	Full term
CCD	charge-coupled devices
FWHM	full width half maximum
MFD	mode field diameter
OTDR	optical time domain reflectometer
RTM	reference test method